

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10670787	HAN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Han, Jason M	2875

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
362	29-30, 97, 260	11/14/2007	JMH
349	70	11/14/2007	JMH

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	10/25/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB) - See Printout	5/8/2007	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	11/14/2007	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	6/2/2008	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	10/27/2008	JMH

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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